


<b>Search Notes</b>  	<b>Application/Control No.</b>  08870762	<b>Applicant(s)/Patent Under Reexamination</b>  DUFT ET AL.
	<b>Examiner</b>  S. Devi, Ph.D.	<b>Art Unit</b>  1645

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Consultations with tQAS Witz & Wax. SPE Eyler & Stucker.	April, 08	SD

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner